



SECTION 2 FORMS PTO/SB/08A and 08B (formerly Form PTO-1449)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Lawrence E. Felton, et al. Attorney Docket: 02550/176
Serial No: 10/657,741 Art Group Unit: 2856
Date Filed: September 8, 2003 Examiner Name: Daniel S. Larkin
Invention: Wafer Level Capped Sensor

LIST OF PATENTS AND PUBLICATIONS FOR
APPLICANT'S SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

U.S. PATENT DOCUMENTS					
Examiner Initials	Reference Number	Document Number	Issue Date	Inventor	Class/Subclass
<i>DL</i>	AM	US6,753,208 B1	June 22, 2004	MacIntyre, D.	438/118
<i>DL</i>	AN	US6,743,656 B2	June 1, 2004	Orcutt, J. et al.	438/66
<i>DL</i>	AO	US6,452,238 B1	Sept. 17, 2002	Orcutt, J. et al.	257/415
<i>DL</i>	AP	US6,384,353 B1	May 7, 2002	Huang, J., et al.	200/181
<i>DL</i>	AQ	US6,307,169 B1	Oct. 23, 2001	Sun, X., et al.	200/181
<i>DL</i>	AR	US6,153,839	Nov. 28, 2000	Zavracky, P., et al.	200/181
<i>DL</i>	AS	US5,872,496	Feb. 16, 1999	Asada, N., et al.	335/78
<i>DL</i>	AT	US5,610,431	March 11, 1997	Martin, J.	257/415
<i>DL</i>	AU	US5,511,428	April 30, 1996	Goldberg, H., et al.	73/777

Examiner Signature: *D. S. L.*

Date Considered: 18 November 2004

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

The Huang et al. reference was previously cited by the examiner in the office action dated 07 July 2004.